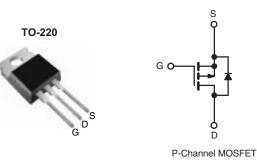
Vishay Siliconix



Power MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	- 100					
R _{DS(on)} (Ω)	V _{GS} = - 10 V 0.30					
Q _g (Max.) (nC)	38					
Q _{gs} (nC)	6.8					
Q _{gd} (nC)	21					
Configuration	Single					



FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- P-Channel
- 175 °C Operating Temperature
- Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION			
Package	TO-220		
Lead (Pb)-free	IRF9530PbF		
Leau (FD)-liee	SiHF9530-E3		
SnPb	IRF9530		
	SiHF9530		

ABSOLUTE MAXIMUM RATINGS T	$C = 25 \ ^{\circ}C$, unless otherw	ise noted			
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V _{DS}	- 100	- v	
Gate-Source Voltage	V _{GS}	± 20			
Continuous Drain Current	V_{GS} at - 10 V $\frac{T_{C} = 25 \degree C}{T_{C} = 100 \degree C}$	I _D	- 12		
	$T_{\rm C} = 100 ^{\circ}{\rm C}$		- 8.2	А	
Pulsed Drain Current ^a	I _{DM}	- 48			
Linear Derating Factor			0.59	W/°C	
Single Pulse Avalanche Energy ^b		E _{AS}	400	mJ	
Repetitive Avalanche Current ^a		I _{AR}	- 12	А	
Repetitive Avalanche Energy ^a	E _{AR}	8.8	mJ		
Maximum Power Dissipation	T _C = 25 °C	PD	88	W	
Peak Diode Recovery dV/dt ^c		dV/dt	- 5.5	V/ns	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 175		
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	- °C	
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
	0-32 OF M3 SCIEW	F	1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. $V_{DD} = -25 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 4.2 mH, $R_G = 25 \Omega$, $I_{AS} = -12 \text{ A}$ (see fig. 12).

c. $I_{SD} \leq$ - 12 A, dl/dt \leq 140 A/µs, $V_{DD} \leq V_{DS}, \, T_J \leq$ 175 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply



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Static VDS	THERMAL RESISTANCE RAT	TINGS							
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	PARAMETER	SYMBOL	TYP. MAX.			UNIT			
Maximum Junction-to-Case (Drain) R_{Buc} - 1.7 SPECIFICATIONS T _J = 25 °C, unless otherwise noted TYP. MAX. U Static Viss Viss = 0 V, I_0 = -250 µA -100 - - - - 0.10 - Viss	Maximum Junction-to-Ambient	R _{thJA}	- 62						
	Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	0.50 -				°C/W	
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Maximum Junction-to-Case (Drain)	R _{thJC}	- 1.7						
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$		unless othern	vise noted						
Static VDB VDB VDB VDB C C C VDB Oraln-Source Breakdown Voltage V_{DS} Reference to 25 °C, tp = -1 mA - - 0.10 - VDB Gate-Source Threshold Voltage $V_{OS}(m)$ $V_{DB} = V_{OS}, t_{D} = -250 \mu A$ -2.0 - 4.0 Gate-Source Leakage Loss $V_{DB} = V_{OS}, t_{D} = -250 \mu A$ - - - 100 - - - - - - - - - - - - - - - 0.00 - - - - 0.00 - - - 0.00 - - - 0.00 - - 0.00 - - 0.00 - 0.00 - 0.00 - 0.00 - 0.00 - 0.00 - 0.00 - 0.00 - 0.00 - 0.00 - 0.00 - 0.00 - 0.00 -						MIN	тур	MAY	UNIT
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$		STMBOL	TEST	CONDIT	10113	IVIIIN.	116.	WAA.	UNIT
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $		V	V - 0		250 4	100	[-	V
					-	- 100			V
Gate-Source Leakage I $_{GSS}$ $V_{GS} = \pm 20$ V - + 100 1 Zero Gate Voltage Drain Current I_{DSS} $V_{DS} = -100$ V, $V_{GS} = 0$ V - - - - - - 100 V Drain-Source On-State Resistance $R_{DS(on)}$ $V_{GS} = -10$ V $I_D = -7.2$ A ^b - - 0.30 Forward Transconductance g_{IS} $V_{GS} = -10$ V $I_D = -7.2$ A ^b - 0.30 Output Capacitance G_{ISS} $V_{DS} = -50$ V, $I_D = -7.2$ A ^b - 0.30 - Output Capacitance C_{ISS} $V_{DS} = -50$ V, $I_D = -7.2$ A ^b 3.7 - - Output Capacitance C_{ISS} $V_{DS} = -50$ V, $I_D = -7.2$ A ^b 3.7 - - 340 - Total Gate Charge Q_{g} $V_{GS} = -10$ V $I_D = -12$ A, $V_{DS} = -80$ V, See fig. 6 and 13 ^b - - 6.8 - - 21 - - 12 - - 12 - 12 - 12 <td< td=""><td></td><td></td><td></td><td></td><td></td><td>-</td><td></td><td></td><td>V/°C</td></td<>						-			V/°C
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	0		-		-	- 2.0		-	V
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Leakage	I _{GSS}				-			nA
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Zero Gate Voltage Drain Current	I _{DSS}						μA	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	-		-	1	-	-	-		-
Dynamic Input Capacitance Ciss $V_{GS} = 0 V$, $V_{DS} = -25 V$, f = 1.0 MHz, see fig. 5 - 860 - Output Capacitance Crss $reverse Transfer Capacitance$ C_{rss} $reverse Transfer Capacitance - 340 - - 340 - - 93 - - 93 - - 340 - - 38 - - 340 - - - 38 - - - 38 - - - 6.8 - - - 6.8 - - - 6.8 - - - 6.8 - - - 6.8 - - - 12 - - 6.8 - - - 12 - - 12 - - 12 - - 131 - - 31 - - 31 - - 33 - - - 12 - - $	Drain-Source On-State Resistance	R _{DS(on)}				-	-	0.30	Ω
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Forward Transconductance	9 _{fs}	V _{DS} = - :	50 V, I _D =	- 7.2 A ^b	3.7	-	-	S
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Dynamic								-
$ \begin{array}{ c c c c c } \hline \text{Output Capacitance} & C_{OSS} & V_{DS} = -25 \text{ V}, & -& 340 & -& -& -& -& -& -& -& -& -& -& -& -& -$	Input Capacitance	C _{iss}		$V_{GS} = 0 V$		-	860	-	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Output Capacitance	C _{oss}	$V_{DS} = -25 V,$		-	340	-	pF	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Reverse Transfer Capacitance	C _{rss}	f = 1.0	MHZ, See	e fig. 5	-	93	-	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Total Gate Charge	Qg			12 A, V _{DS} = - 80 V,	-	-	38	nC
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Charge	Q _{gs}	V _{GS} = - 10 V	I _D = - 12		-	-	6.8	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Drain Charge	Q _{gd}		0001	ig. o and to	-	-	21	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Turn-On Delay Time	t _{d(on)}				-	12	-	
$\begin{tabular}{ c c c c c c } \hline Turn-Off Delay Time & t_d(off) & R_G = 12 \ \Omega, R_D = 3.9 \ \Omega, see fig. 10^b & - & 31 & - & \\ \hline Fall Time & t_f & - & 39 & - & \\ \hline Internal Drain Inductance & L_D & Between lead, & & & & & & \\ f mm (0.25") from & & & & f mm (0.25") from & & & & & \\ p ackage and center of & & & & & & \\ \hline Internal Source Inductance & L_S & & & & & \\ \hline Drain-Source Body Diode Characteristics & & & & & & \\ \hline Drain-Source Drain Diode Current & I_S & MOSFET symbol & & & & & & \\ Pulsed Diode Forward Current^a & I_{SM} & & & & & \\ \hline Integral reverse & & & & & & \\ \hline Dody Diode Voltage & V_{SD} & T_J = 25 \ C, \ I_F = -12 \ A, \ dl/dt = 100 \ A/\mus^b & - & & & & \\ \hline 1 & 120 & 240 & & \\ \hline 1 & 0.46 & 0.92 &$	Rise Time			50 V. In =	- 12 A.	-	52	-	
Fall Timetr-39-Internal Drain Inductance L_D Between lead, 6 mm (0.25") from package and center of die contact-4.5-Internal Source Inductance L_S L_S 7.5-Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode Current I_S MOSFET symbol showing the integral reverse $p - n$ junction diode12Pulsed Diode Forward Currenta I_{SM} $T_J = 25 ^\circ C$, $I_S = -12 A$, $V_{GS} = 0 V^b$ Body Diode Reverse Recovery Time t_{rr} $T_J = 25 ^\circ C$, $I_F = -12 A$, $dI/dt = 100 A/\mu s^b$ -120240-Body Diode Reverse Recovery Charge Q_{rr} $T_J = 25 ^\circ C$, $I_F = -12 A$, $dI/dt = 100 A/\mu s^b$ -0.460.92-	Turn-Off Delay Time	t _{d(off)}			-	31	-	ns	
Internal Drain inductanceLD6 mm (0.25") from package and center of die contact-4.3-Internal Source InductanceLS L_S -7.5-Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode CurrentISMOSFET symbol showing the integral reverse $p - n$ junction diode12Pulsed Diode Forward CurrentaISMT_J = 25 °C, I_S = - 12 A, V_{GS} = 0 VbBody Diode Reverse Recovery TimetrrT_J = 25 °C, I_F = - 12 A, dl/dt = 100 A/µsb6.3Body Diode Reverse Recovery ChargeQrrT_J = 25 °C, I_F = - 12 A, dl/dt = 100 A/µsb-0.460.921	Fall Time					-	39	-	
Internal Source InductanceLS $Pachage and context of the output of$	Internal Drain Inductance	L _D	6 mm (0.25") from ackage and center of		-	4.5	-		
Continuous Source-Drain Diode CurrentIsMOSFET symbol showing the integral reverse p - n junction diode12Pulsed Diode Forward CurrentaIsmIsmT_J = 25 °C, I_S = - 12 A, V_{GS} = 0 V^b <td>Internal Source Inductance</td> <td>Ls</td> <td>-</td> <td>7.5</td> <td>-</td> <td>nH</td>	Internal Source Inductance	Ls			-	7.5	-	nH	
Contributes Source-Drain Diode OutlentIsshowing the integral reverse p - n junction diodeIsIsPulsed Diode Forward Currenta I_{SM} I_{SM} $T_J = 25 \text{ °C}, I_S = -12 \text{ A}, V_{GS} = 0 \text{ Vb}$ 48Body Diode Voltage V_{SD} $T_J = 25 \text{ °C}, I_S = -12 \text{ A}, V_{GS} = 0 \text{ Vb}$ 6.3Body Diode Reverse Recovery Time t_{rr} $T_J = 25 \text{ °C}, I_F = -12 \text{ A}, dI/dt = 100 \text{ A/µsb}$ -120240Body Diode Reverse Recovery Charge Q_{rr} 0.460.921	Drain-Source Body Diode Characteristic	s							
Pulsed Diode Forward CurrentaI I SMIntegral reverse p - n junction diode48Body Diode VoltageV SDT T J = 25 °C, I S = - 12 A, V GS = 0 Vb48Body Diode Reverse Recovery Timetrr Tr OutputT T J = 25 °C, I F = - 12 A, dI/dt = 100 A/µsb6.3Body Diode Reverse Recovery ChargeQ rrT OutputT T Output-1202400.460.92-	Continuous Source-Drain Diode Current	I _S	showing the integral reverse		-	-	- 12	A	
Body Diode Reverse Recovery Time t_{rr} $T_J = 25 \ ^{\circ}C$, $I_F = -12 \ ^{\circ}A$, $dI/dt = 100 \ ^{\circ}A/\mu s^b$ $ 120$ 240 Body Diode Reverse Recovery Charge Q_{rr} $T_J = 25 \ ^{\circ}C$, $I_F = -12 \ ^{\circ}A$, $dI/dt = 100 \ ^{\circ}A/\mu s^b$ $ 0.46$ 0.92	Pulsed Diode Forward Currenta	I _{SM}			-	-	- 48		
Body Diode Reverse Recovery Time t_{rr} $T_J = 25 \ ^{\circ}C$, $I_F = -12 \ ^{\circ}A$, $dl/dt = 100 \ ^{\prime}A/\mu s^b$ $ 120$ 240 Body Diode Reverse Recovery Charge Q_{rr} $T_J = 25 \ ^{\circ}C$, $I_F = -12 \ ^{\circ}A$, $dl/dt = 100 \ ^{\prime}A/\mu s^b$ $ 0.46$ 0.92	Body Diode Voltage	V _{SD}	$T_J = 25 \text{ °C}, I_S = -12 \text{ A}, V_{GS} = 0 \text{ V}^{b}$		-	-	- 6.3	V	
Body Diode Reverse Recovery Charge Q_{rr} $I_J = 25 \ ^{\circ}C$, $I_F = -12 \ ^{\circ}A$, $dI/dt = 100 \ ^{\circ}A/\mu s^0$ -0.460.92I	Body Diode Reverse Recovery Time				-	120	240	ns	
	Body Diode Reverse Recovery Charge				-	0.46	0.92	μC	
Forward Turn-On Time ton Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)	Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn			-on is don	ninated by	/ L _S and I	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



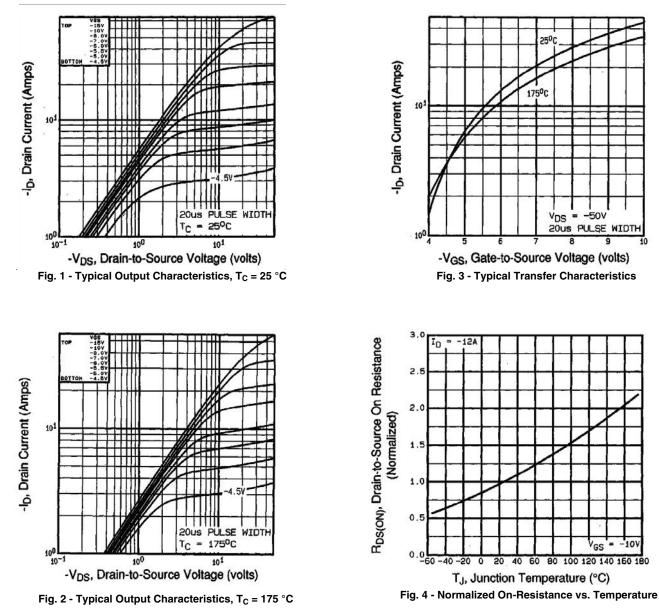
175⁰C

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V_{DS} = -50V 20us PULSE WIDTH

8





10

GS

20 40 60 80 100 120 140 160 180

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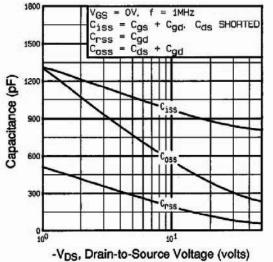


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

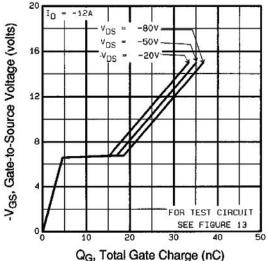
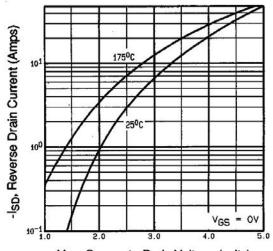
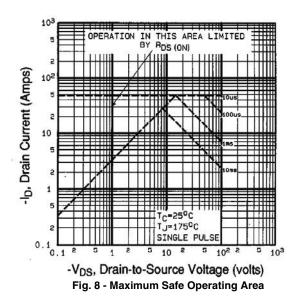


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



-V_{SD}, Source-to-Drain Voltage (volts) Fig. 7 - Typical Source-Drain Diode Forward Voltage





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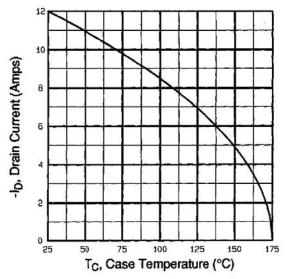


Fig. 9 - Maximum Drain Current vs. Case Temperature

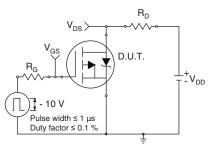


Fig. 10a - Switching Time Test Circuit

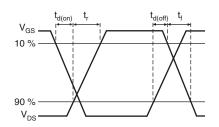


Fig. 10b - Switching Time Waveforms

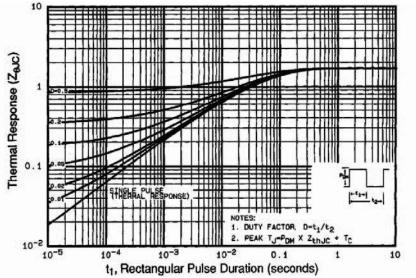


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

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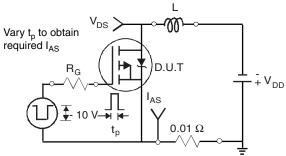
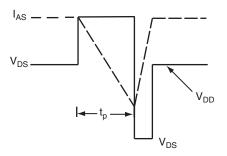
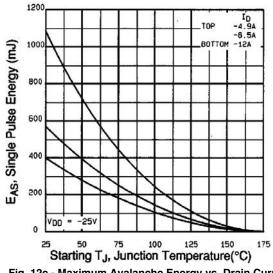


Fig. 12a - Unclamped Inductive Test Circuit



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Fig. 12b - Unclamped Inductive Waveforms





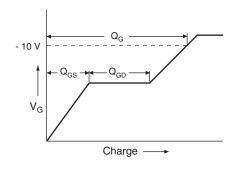
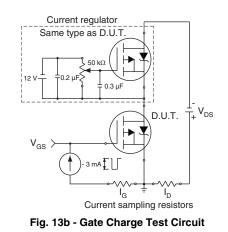
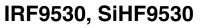


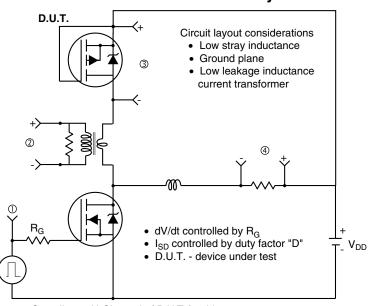
Fig. 13a - Basic Gate Charge Waveform





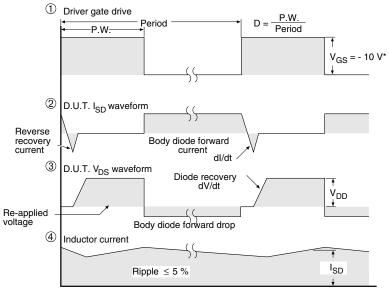
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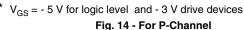




Peak Diode Recovery dV/dt Test Circuit

• Compliment N-Channel of D.U.T. for driver





Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see http://www.vishay.com/ppg?91076.



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